

<b>Notice of References Cited</b>	Application/Control No. 10/796,599		Applicant(s)/Patent Under Reexamination FENG, WEISHI	
	Examiner MARTIN JERIKO P. SAN JUAN		Art Unit 2132	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,683,954 B1	01-2004	Searle, Scott	380/30
*	B	US-7,380,135 B2	05-2008	Nishimoto et al.	713/193
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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